

**Search Notes**

Application/Control No.

10/511,792

Examiner

Chris C. Chu

Applicant(s)/Patent under  
Reexamination

RADENNE ET AL.

Art Unit

2815

**SEARCHED**

Class	Subclass	Date	Examiner
257	E21.501, E23.064 & E23.14	9/11/2007	C.C.
257	678 - 681	9/11/2007	C.C.
235	492 & 488	9/11/2007	C.C.
235	487 & 380	9/11/2007	C.C.
235	451	9/11/2007	C.C.
29	827	9/11/2007	C.C.
361	737 & 761	9/11/2007	C.C.
174	52.4&521	9/11/2007	C.C.
156	252 & 253	9/11/2007	C.C.
156	261 & 293	9/11/2007	C.C.
156	295	9/11/2007	C.C.
156	244.12	9/11/2007	C.C.

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
As same	as above	9/11/2007	C.C.

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Searched in US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; FPRS; and IBM_TDB;	9/11/2007	C.C.